MAX3221 3-V TO 5.5-V MULTICHANNEL RS-232 LINE DRIVER/RECEIVER

- Meets or Exceeds the Requirements of TIA/EIA-232-F and ITU v.28 Standards
- Operates With 3-V to 5.5-V V_{CC} Supply
- Operates up to 250 kbit/s
- Low Standby Current . . . 1 µA Typical
- External Capacitors . . . 4 \times 0.1 μ F
- Accepts 5-V Logic Input With 3.3-V Supply
- **Designed to Be Interchangeable With** Maxim MAX3221
- **RS-232 Bus-Pin ESD Protection Exceeds** ±15-kV Using Human-Body Model (HBM)
- **Applications**
 - Battery-Powered Systems, PDAs, Notebooks, Laptops, Palmtop PCs, and Hand-Held Equipment
- Package Options Include Plastic Shrink Small-Outline (DB) and Thin Shrink Small-Outline (PW) Packages

description

The MAX3221 device consists of one line driver, one line receiver, and a dual charge-pump circuit with ±15-kV ESD protection pin to pin (serial-port connection pins, including GND). The device meets the requirements of TIA/EIA-232-F and provides the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. These devices operate at data signaling rates up to 250 kbit/s, and at a maximum of 30-V/ μ s driver output slew rate.

Flexible control options for power management are available when the serial port is inactive. The auto-powerdown feature functions when FORCEON is low and FORCEOFF is high. During this mode of operation, if the device does not sense a valid RS-232 signal, the driver outputs are disabled. If FORCEOFF is set low and \overline{EN} is high, both drivers and receivers are shut off, and the supply current is reduced to 1 μ A. Disconnecting the serial port or turning off the peripheral drivers causes the auto-powerdown condition to occur. Auto-powerdown can be disabled when FORCEON and FORCEOFF are high. With auto-powerdown enabled, the device is activated automatically when a valid signal is applied to any receiver input. The INVALID output notifies the user if an RS-232 signal is present at any receiver input. INVALID is high (valid data) if any receiver input voltage is greater than 2.7 V or less than -2.7 V, or has been between -0.3 V and 0.3 V for less than 30 μ s. INVALID is low (invalid data) if the receiver input voltage is between –0.3 V and 0.3 V for more than 30 μ s. Refer to Figure 5 for receiver input levels.

The MAX3221C is characterized for operation from 0°C to 70°C. The MAX3221I is characterized for operation from -40°C to 85°C.

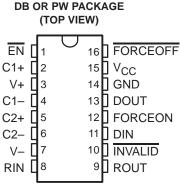


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



SLLS348B - JUNE 1999 - REVISED JANUARY 2000



	AVAILABLE OPTIC	ONS
	PACKAGE	DEVICES
TA	SHRINK SMALL OUTLINE (DB)	THIN SHRINK SMALL OUTLINE (PW)
0°C to 70°C	MAX3221CDB	MAX3221CPW
-40° C to 85° C	MAX3221IDB	MAX3221IPW

The DB and PW packages are available taped and reeled. Add the suffix R to device type (e.g., MAX3221CDBR).

Function Tables

EACH DRIVER

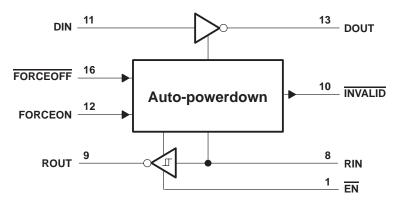
		INPUTS	-	OUTPUT	
DIN	FORCEON	FORCEOFF	VALID RIN RS-232 LEVEL	DOUT	DRIVER STATUS
Х	Х	L	Х	Z	Powered off
L	Н	Н	Х	Н	Normal operation with
н	Н	Н	Х	L	auto-powerdown disabled
L	L	Н	Yes	Н	Normal operation with
н	L	Н	Yes	L	auto-powerdown enabled
L	L	Н	No	Z	Powered off by
н	L	Н	No	Z	auto-powerdown feature

H = high level, L = low level, X = irrelevant, Z = high impedance

	EA	CH RECEIVER	
	INP	UTS	OUTPUT
RIN	EN	VALID RIN RS-232 LEVEL	ROUT
L	L	Х	Н
н	L	Х	L
Х	Н	Х	Z
Open	L	No	Н

H = high level, L = low level, X = irrelevant, Z = high impedance (off), Open = disconnected input or connected driver off

logic diagram (positive logic)





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Storage temperature range, T _{stg}	Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	$\begin{array}{cccc} -0.3 \ V \ to \ 7 \ V \\ \hline 0.3 \ V \ to \ -7 \ V \\ \hline 13 \ V \\ \hline -0.3 \ V \ to \ 6 \ V \\ \hline -25 \ V \ to \ 25 \ V \\ \hline -13.2 \ V \ to \ 13.2 \ V \\ \hline -0.3 \ V \ to \ V_{CC} \ + \ 0.3 \ V \\ \hline 82^\circ C/W \\ \hline 108^\circ C/W \\ \hline 260^\circ C \end{array}$

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages are with respect to network GND.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3 and Figure 6)

				MIN	NOM	MAX	UNIT
	Supply voltage		V _{CC} = 3.3 V	3	3.3	3.6	V
	Supply voltage		$V_{CC} = 5 V$	4.5	5	5.5	v
	Driver and control high-level input voltage	DIN, FORCEOFF, FORCEON,	V _{CC} = 3.3 V	2			V
VIH	Driver and control high-level input voltage	EN	$V_{CC} = 5 V$	2.4			v
V_{IL}	Driver and control low-level input voltage	DIN, FORCEOFF, FORCEON, EN	Ī			0.8	V
VI	Driver and control input voltage	DIN, FORCEOFF, FORCEON		0		5.5	V
VI	Receiver input voltage			-25		25	V
т.	Operating free-air temperature		MAX3221C	0		70	°C
TA			MAX3221I	-40		85	C

NOTE 3: Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V ± 0.5 V.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAM	ETER	TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
Ц	Input leakage current	FORCEOFF, FORCEON, EN			±0.01	±1	μΑ
		Auto-powerdown disabled	No load, FORCEON at V_{CC}		0.3	1	mA
Icc	Supply current	Powered off	No load, FORCEOFF at GND		1	10	
	Supply current Powered off	Auto-powerdown enabled	No load, FORCEOFF at V _{CC} , FORCEON at GND, All RIN are open or grounded		1	10	μΑ

[‡] All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C. NOTE 3: Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V ± 0.5 V.



DRIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAMETER	TEST C	ONDITIONS		MIN	TYP†	MAX	UNIT
∨он	High-level output voltage	DOUT at $R_L = 3 k\Omega$ to GND,	DIN = GND		5	5.4		V
VOL	Low-level output voltage	DOUT at $R_L = 3 k\Omega$ to GND,	$DIN = V_{CC}$		-5	-5.4		V
Чн	High-level input current	$V_I = V_{CC}$				±0.01	±1	μΑ
١ _{IL}	Low-level input current	V _I at GND				±0.01	±1	μΑ
1.0.0	o , , , , , , , , , , , , , , , , , , ,	V _{CC} = 3.6 V,	VO = 0 V			±35	+60	mA
los	Short-circuit output current [‡]	$V_{CC} = 5.5 V,$	$V_{O} = 0 V$			±35	±00	mA
r _o	Output resistance	V_{CC} , V+, and V– = 0 V,	$V_{O} = \pm 2 V$		300	10M		Ω
loff	Output leakage current	FORCEOFF = GND,	$V_{O} = \pm 12 V$,	V_{CC} = 0 to 5.5 V			±25	μΑ

[†] All typical values are at $V_{CC} = 3.3$ V or $V_{CC} = 5$ V, and $T_A = 25^{\circ}$ C.

[‡] Short-circuit durations should be controlled to prevent exceeding the device absolute power dissipation ratings, and not more than one output should be shorted at a time.

NOTE 3: Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAMETER	TEST CON	IDITIONS	MIN	TYP†	MAX	UNIT
	Maximum data rate	C _L = 1000 pF,	$R_L = 3 k\Omega$, See Figure 1	250			kbit/s
^t sk(p)	Pulse skew [§]	C _L = 150 pF to 2500 pF	$R_L = 3 k\Omega$ to 7 kΩ See Figure 2		100		ns
SR(tr)	Slew rate, transition region	V _{CC} = 3.3 V,	C _L = 150 pF to 1000 pF	6		30	V/µs
SK(ii)	(see Figure 1)	$R_L = 3 k\Omega$ to 7 k Ω	C _L = 150 pF to 2500 pF	4		30	v/µs

[†] All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

 $Pulse skew is defined as <math display="inline">|t_{PLH}-t_{PHL}|$ of each channel of the same device.

NOTE 3: Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V ± 0.5 V.



RECEIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3 and Figure 6)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
VOH	High-level output voltage	$I_{OH} = -1 \text{ mA}$	V _{CC} – 0.6 V	$V_{CC} - 0.1 V$		V
VOL	Low-level output voltage	I _{OL} = 1.6 mA			0.4	V
VIT+	Positive-going input threshold voltage	V _{CC} = 3.3 V		1.6	2.4	V
VII+	Positive-going input timeshold voltage	$V_{CC} = 5 V$		1.9	2.4	
V	Negative-going input threshold voltage	V _{CC} = 3.3 V	0.6	1.1		V
VIT-	Negative-going input threshold voltage	$V_{CC} = 5 V$	0.8	1.4		v
V _{hys}	Input hysteresis (V _{IT+} – V _{IT} –)			0.5		V
loff	Output leakage current	FORCEOFF = 0 V		±0.05	±10	μΑ
rj	Input resistance	$V_{I} = \pm 3 V \text{ to } \pm 25 V$	3	5	7	kΩ

[†] All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

NOTE 3: Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V ± 0.5 V.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Note 3)

	PARAMETER	TEST CONDITIONS	MIN TYP [†]	MAX	UNIT
^t PLH	Propagation delay time, low- to high-level output		150		ns
^t PHL	Propagation delay time, high- to low-level output	C _L = 150 pF, See Figure 3	150		ns
t _{en}	Output enable time	$C_L = 150 \text{ pF}, R_L = 3 \text{ k}\Omega$, See Figure 4	200		ns
^t dis	Output disable time	$C_{L} = 150 \text{ pr}, \text{K}_{L} = 3 \text{K}_{2} \text{, See Figure 4}$	200		ns
^t sk(p)	Pulse skew [‡]	See Figure 3	50		ns

[†] All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

[‡] Pulse skew is defined as $|t_{PLH} - t_{PHL}|$ of each channel of the same device. NOTE 3: Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V ± 0.5 V.



AUTO-POWERDOWN SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
V _{T+(valid)}	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V _{CC}			2.7	V
V _{T-(valid)}	Receiver input threshold for INVALID high-level output voltage	FORCEON = GND, FORCEOFF = V _{CC}	-2.7			V
V _{T(invalid)}	Receiver input threshold for (INVALID) low-level output voltage	FORCEON = GND, FORCEOFF = V _{CC}	-0.3		0.3	V
VOH	INVALID high-level output voltage	$I_{OH} = -1 \text{ mA}$, FORCEON = GND, FORCEOFF = V _{CC}	V _{CC} – 0.6			V
VOL	INVALID low-level output voltage	$I_{OL} = 1.6 \text{ mA}$, FORCEON = GND, FORCEOFF = V _{CC}			0.4	V

[†] All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 5)

	PARAMETER	MIN TYP [†]	MAX	UNIT
t _{valid}	Propagation delay time, low- to high-level output	1		μs
^t invalid	Propagation delay time, high- to low-level output	30		μs
t _{en}	Supply enable time	100		μs

[†] All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.



VOLTAGE WAVEFORMS

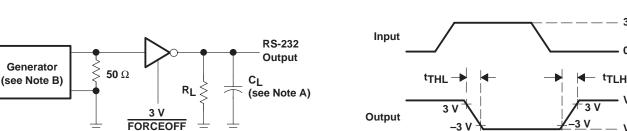
VOLTAGE WAVEFORMS

3 V

0 V

۷он

VOL



SR(tr) =

PARAMETER MEASUREMENT INFORMATION

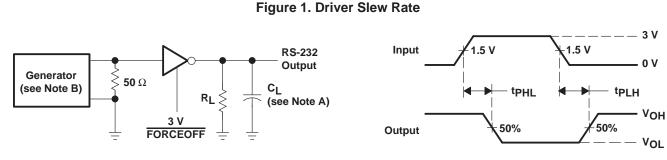
TEST CIRCUIT

NOTES: A. CL includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_0 = 50 \Omega$, 50% duty cycle, $t_f \le 10$ ns, $t_f \le 10$ ns.

6 V

t_{THL} or t_{TLH}

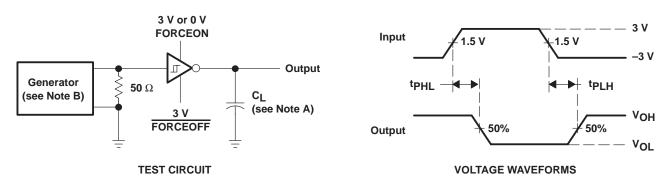


TEST CIRCUIT

NOTES: A. C_I includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_O = 50 \Omega$, 50% duty cycle, $t_r \le 10$ ns, $t_f \le 10$ ns.

Figure 2. Driver Pulse Skew

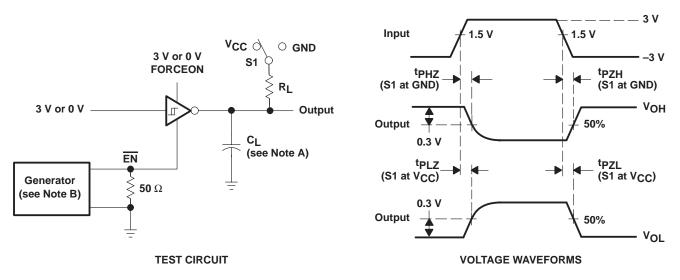


NOTES: A. CL includes probe and jig capacitance.

B. The pulse generator has the following characteristics: $Z_O = 50 \Omega$, 50% duty cycle, $t_f \le 10$ ns. $t_f \le 10$ ns.

Figure 3. Receiver Propagation Delay Times





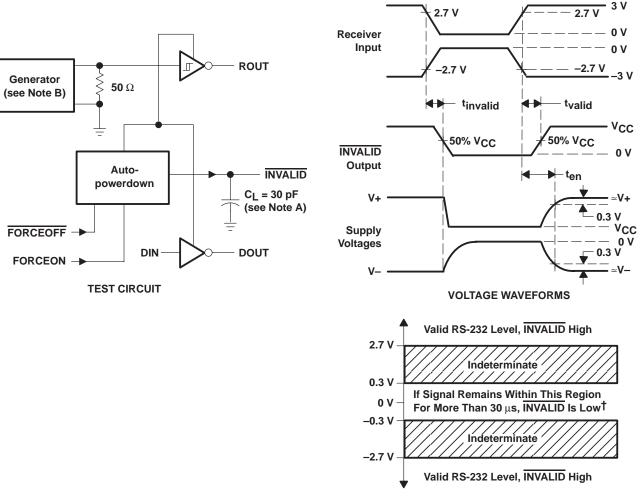
PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. The pulse generator has the following characteristics: $Z_0 = 50 \Omega$, 50% duty cycle, $t_f \le 10 \text{ ns}$.
- C. tpLZ and tpHZ are the same as tdis.
- D. tPZL and tPZH are the same as ten.

Figure 4. Receiver Enable and Disable Times





PARAMETER MEASUREMENT INFORMATION

 † Auto-powerdown disables drivers and reduces supply current to 1 $\mu A.$

NOTES: A. CL includes probe and jig capacitance.

B. The pulse generator has the following characteristics: PRR = 5 kbit/s, $Z_0 = 50 \Omega$, 50% duty cycle, $t_f \le 10$ ns. $t_f \le 10$ ns.

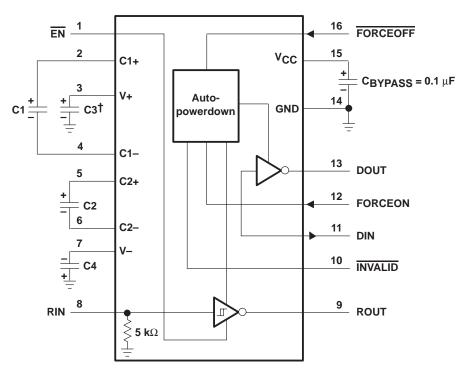
Figure 5. INVALID Propagation Delay Times and Driver Enabling Time





MAX3221 3-V TO 5.5-V MULTICHANNEL RS-232 LINE DRIVER/RECEIVER

SLLS348B - JUNE 1999 - REVISED JANUARY 2000



APPLICATION INFORMATION

 $^{+}$ C3 can be connected to V_{CC} or GND.

NOTE A: Resistor values shown are nominal.

V _{CC}	C1	C2, C3, and C4
$\begin{array}{c} \textbf{3.3 V} \pm \textbf{0.3 V} \\ \textbf{5 V} \pm \textbf{0.5 V} \\ \textbf{3 V to 5.5 V} \end{array}$	0.1 μF 0.047 μF 0.1 μF	0.1 μF 0.33 μF 0.47 μF

Figure 6. Typical Operating Circuit and Capacitor Values





IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 2000, Texas Instruments Incorporated